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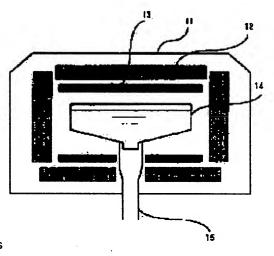
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## (54) PRODUCTION APPARATUS FOR FLUORITE OF LARGE DIAMETER AND ITS PRODUCTION (57)Abstract:

PROBLEM TO BE SOLVED: To obtain a single crystal of large diameter, by arranging a crucible in a vacuum electric furnace having a ceiling heater and a bottom heater, uniforming the temperature of a melt in the interior of the crucible in the radius direction, making a temperature gradient in the growth direction of a single crystal and growing crystal.

SOLUTION: A crucible 14 supported on a supporting rod 15, a ceiling heater 13, a bottom heater, etc., are arranged in the interior of a bell jar 11 of a vacuum electric furnace and a thermocouple is placed in the vicinity of each heater to carry out control in quick response. In order to prevent a solidified part from cracking, the height of an ingot is ≤200 mm. Then an electric source is applied, the ceiling heater 13 is made about 1,550°C and the bottom heater about 1390°C so as to give 8 k/cm temperature gradient. The temperature difference of 160°C is maintained to grow crystal with reducing temperature at 1°C per hour. After the ceiling heater 13 is dropped to about 1,350°C, both the heaters are adjusted to about 1,300°C and the ingot is gradually cooled so that it is not cracked to give a single crystal having ≥250 mm diameter.



## **LEGAL STATUS**

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